



TOSHIBA Insulated Gate Bipolar Transistor Silicon N Channel MOS Type

GT5G102

Unit in mm

Strobe Flash Applications

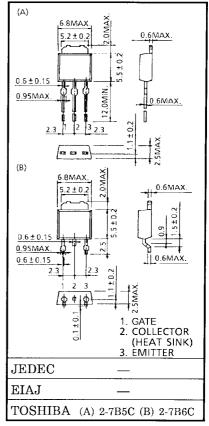
- 3rd Generation
- High input impedance
- Low saturation voltage $: V_{CE} (sat) = 8 V (max) (I_C = 130 A)$
- Enhancement-mode
- 12 V gate drive



Collector

Maximum Ratings ($Ta = 25^{\circ}C$)

Characteristics		Symbol	Rating	Unit	
Collector-emitter voltage		V _{CES}	400	V	
Gate-emitter voltage	DC	V _{GES}	±20	V	
Collector current	DC	Ι _C	5	А	
	1 ms	I _{CP}	130	А	
Collector power dissipation	Ta = 25°C	P _C	1.3	W	
	$Tc = 25^{\circ}C$	P _C	20	W	
Junction temperature		Tj	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	



Weight: 0.36 g

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Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GES}	$V_{GE} = 20 \text{ V}, V_{CE} = 0$			10	μΑ
Collector cut-off current		ICES	$V_{CE} = 400 \text{ V}, \text{ V}_{GE} = 0$	_		10	μA
Gate-emitter cut-off voltage		V _{GE (OFF)}	$I_C = 1 \text{ mA}, V_{CE} = 5 \text{ V}$	2	—	5	V
Collector-emitter saturation voltage		V _{CE (sat)}	$I_C = 130 \text{ A}, V_{GE} = 12 \text{ V} \text{ (pulsed)}$		5	8	V
Input capacitance		Cies	$V_{CE} = 10 \text{ V}, \text{ V}_{GE} = 0, \text{ f} = 1 \text{ MHz}$		1200		pF
Switching time	Rise time	t _r	$\begin{array}{c} 12 \ V \\ 0 \end{array} \qquad \begin{array}{c} 51 \ \Omega \\ \hline \\ V_{\text{IN}}: t_{\text{f}} \leq 100 \ \text{ns} \\ t_{\text{f}} \leq 100 \ \text{ns} \end{array} \qquad \begin{array}{c} 70 \\ \hline \\ 300 \ V \\ \hline \\ \text{Duty cycle} \leq 1\% \end{array}$		0.7		μs
	Turn-on time	t _{on}		_	0.9	_	
	Fall time	t _f			1.7	_	
	Turn-off time	t _{off}		_	2.0	_	
Thermal resistance		R _{th (j-c)}	—		—	6.25	°C/W

This transistor is an electrostatic sensitive device. Please handle with caution.